

RELIABILITY DATA

LT1030

8/21/2006

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
PLASTIC DIP	44	8701	8701	139.46	0
	44			139.46	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP	1,628	8644	9640	371.11	1
SOIC/SOT/MSOP	1,407	9041	9627	48.20	0
	3,035			419.31	1

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
PLASTIC DIP	274	9109	9640	35.17	0
SOIC/SOT/MSOP	150	9617	9723	15.00	0
	424			50.17	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
PLASTIC DIP	202	8730	9451	20.20	0
SOIC/SOT/MSOP	139	9351	9702	13.90	0
	341			34.10	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 13.19 FITS

(3) Mean Time Between Failures in Years = 8,649

Note: 1 FIT = 1 Failure in One Billion Hours.